

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L5	614794	(position align\$4 pre\$1position pre\$1align\$4) and (substrate wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 07:25
L6	15967	L5 and (determine measure) and (chuck fasten secure) and @pd<"20030131"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 08:13
L7	1846	L6 and ((error problem remove misalign\$4) adj3 (substrate wafer chip))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 08:14
L8	271	L7 and ((correct\$3 reposition recalibrat\$3) adj3 (chip substrate wafer))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 08:14
L9	662	L6 and ((error problem "can not" fail\$3) adj3 (align\$4 position))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 07:29
L10	213	L9 and ((abort stop end) adj3 (process align\$4 position\$3 calibrat\$3))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 08:14
L14	16	L10 and ((damage\$1 unuseable scratch\$2 defect\$3) near3 (chip substrate wafer))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 07:38
L15	2	("4557599" "6237393").pn.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 07:43
L16	24	L9 and ((abort stop end) adj3 (process align\$4 position\$3 calibrat\$3)) and ((remove "take out" replace) adj3 (chip substrate wafer))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 08:15
S18	611	(hiroshi and kusumoto).in.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/22 08:12
S19	534	(hiroshi and kusumoto).in. and @pd<"20030131"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/22 08:12

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S20	613937	(position align\$4 pre\$1position pre\$1align\$4) and (substrate wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 12:57
S21	24945	(250/548,559.29,559.3 355/53,55, 77 356/399-401,614 382/151-153 414/935-941 430/5,22,30 438/5,7, 14,16 700/56-66 702/94,95, 150-154).ccls. and @pd<"20030131"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/22 08:12
S22	8949	S21 and S20	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/22 08:12
S23	8	(hiroshi and kusumoto).in. and @pd<"20030131" and align	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/22 08:27
S40	1	(taniguchi and yoshihisa) and substrate and chucking and apparatus	US-PGPUB; USPAT; USOCR	OR	ON	2006/03/22 13:24
S46	15967	S20 and (determine measure) and (chuck fasten secure) and @pd<"20030131"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 07:04
S47	1846	S46 and ((error problem remove misalign\$4) adj3 (substrate wafer chip))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 13:55
S48	39	S47 and ((move position align\$4 pre\$1position pre\$1align\$4) adj2 (substrate wafer)) and ((determine measure possible) adj3 (chuck fasten secure))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/22 13:42
S49	3	S47 and ((can\$not fail)adj3 chuck)	US-PGPUB; USPAT; USOCR	OR	ON	2006/03/22 13:50
S50	6504	S46 and (perpendicular orthogonal orthoganal orthonormal)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/22 13:46
S51	2077	S46 and ((perpendicular orthogonal orthoganal orthonormal) adj3 (rotation axis chip wafer))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/22 14:02
S52	1364	S46 and ((error problem remove misalign\$4) adj2 (substrate wafer chip))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/22 13:50

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S53	838	S46 and ((error problem remove misalign\$4) adj (substrate wafer chip))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/22 13:50
S54	118	S46 and ((can\$not fail\$3) adj3 (hold grasp chuck seal))	US-PGPUB; USPAT; USOCR	OR	ON	2006/03/22 14:02
S55	4	S46 and ((can\$not fail\$3) adj3 (hold grasp chuck seal)) same (remove eject repeat)	US-PGPUB; USPAT; USOCR	OR	ON	2006/03/22 13:52
S60	1715	S46 and ((perpendicular orthogonal orthogonal orthonormal) adj2 (axis))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/22 14:03
S61	366	S46 and ((align set place move) adj3 (wafer chip)) and ((perpendicular orthogonal orthogonal orthonormal) adj3 (rotation axis))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/22 14:04
S62	46	S20 and ((determine measure "find out") adj (chuck\$2 fasten\$2 secure\$2 hold held)) and @pd<"20030131"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/22 14:06
S63	15	("5103367"   "5117121"   "5221450"   "5436790"   "5444597"   "5463526"   "5507874"   "5557215"   "5671119"   "5699223"   "5712702"   "5751537").PN. OR ("5886865").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/03/22 14:18
S64	10	("4026031"   "4457664"   "4752898"   "4765793"   "4833790"   "4846626"   "4880348"   "4887904"   "4907035"   "4938654").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/03/22 16:00
S67	614794	(position align\$4 pre\$1position pre\$1align\$4) and (substrate wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/23 07:36
S71	15967	S67 and (determine measure) and (chuck fasten secure) and @pd<"20030131"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/23 07:23
S72	1846	S71 and ((error problem remove misalign\$4) adj3 (substrate wafer chip))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/23 08:48
S87	17994	S67 and ((error problem cannot fail) adj3 (position\$3 align\$4 chuck fasten)) and (substrate wafer chip)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/23 07:25

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S88	506	S67 and ((error problem cannot fail) adj3 (position\$3 align\$4 chuck fasten)) and ((remove eject "take out") adj3 (substrate wafer chip))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/23 07:27
S92	67	S67 and ((error problem cannot fail) adj3 (position\$3 align\$4 chuck fasten seal grasp) adj4 (chip substrate wafer)) and ((eject remove "take out" "taken out") adj3 (chip substrate wafer)) and @pd<"20030131"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/23 07:41
S95	493243	(position align\$4 pre\$1position pre\$1align\$4) and (chip substrate wafer) and @pd<"20030131"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/23 07:40
S96	1635	S95 and ((test check insure determine) adj3 (chuck fasten seal grip vacuum))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/23 09:12
S97	12	S96 and (((error cannot "can not" problem fail) adj3 (fasten secure chuck hold)) same ((remove eject eliminate ) adj "3" (chip substrate wafer)))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 08:08
S98	941	S95 and ((test check insure determine) adj3 (chuck fasten seal grip))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/23 09:13
S100	115	S96 and ((error cannot "can not" problem fail) adj3 (fasten secure chuck hold vacuum))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/23 09:20
S101	1	"5715064".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/27 07:43
S102	6	("4112736"   "4458519"   "4901431"   "5381962"   "5522267"   "5553376").PN. OR ("5925835").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/03/23 09:36
S103	17	("3800264"   "4276533"   "4322980"   "4399707"   "4691575"   "4763098").PN. OR ("5522267").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/03/23 09:37
S104	1	"4648708".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 08:46

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S10 5	614794	(position align\$4 pre\$1position pre\$1align\$4) and (substrate wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 07:04
S10 6	15967	S105 and (determine measure) and (chuck fasten secure) and @pd<"20030131"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 07:05
S10 7	0	S106 and ((mark point) adj "on the" adj (substrate wafer chip))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 07:07
S10 8	1415	S106 and ((mark point) adj2 (substrate wafer chip))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 07:07
S10 9	142	S106 and (((mark point) adj3 (substrate wafer chip)) same ((mark point) adj3 (pad stage holder plate)))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 07:12
S11 0	493243	(position align\$4 pre\$1position pre\$1align\$4) and (chip substrate wafer) and @pd<"20030131"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 07:09
S11 1	1635	S110 and ((test check insure determine) adj3 (chuck fasten seal grip vacuum))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 08:12
S11 2	115	S111 and ((error cannot "can not" problem fail) adj3 (fasten secure chuck hold vacuum))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 07:09
S11 3	142	S109 not S112	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 07:09
S11 4	83	S106 and (((mark point) adj3 (substrate wafer chip)) same (align position) same ((mark point) adj3 (pad stage holder plate)))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 07:13
S11 5	6	S111 and (((error cannot "can not" problem fail) adj3 (fasten secure chuck hold grip)) adj3 (chip substrate wafer))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 08:12
S11 9	131	(chuck\$3 same (substrate wafer)) same (correct\$3 near (position\$3 align\$4)) and @pd<"20030131"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 12:58

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S12 0	493243	(position align\$4 pre\$1position pre\$1align\$4) and (chip substrate wafer) and @pd<"20030131"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 12:57
S12 1	151	S120 and (chuck\$3 same (chip substrate wafer)) same (correct\$3 near (position\$3 align\$4))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 12:59
S12 2	17	S120 and (chuck\$3 same (chip substrate wafer)) same (calibrat\$3 same (calibrat\$3 near (position\$3 align\$4)))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 13:02
S12 3	614794	(position align\$4 pre\$1position pre\$1align\$4) and (substrate wafer)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 13:58
S12 4	15967	S123 and (determine measure) and (chuck fasten secure) and @pd<"20030131"	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 13:59
S12 5	1846	S124 and ((error problem remove misalign\$4) adj3 (substrate wafer chip))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 13:59
S12 6	1242	S125 and ((move reposition position calibrat\$3) adj3 (chip substrate wafer))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 14:00
S12 7	271	S125 and ((correct\$3 reposition recalibrat\$3) adj3 (chip substrate wafer))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/03/24 14:00